
Fundamentals of Sigma-Delta ADCs

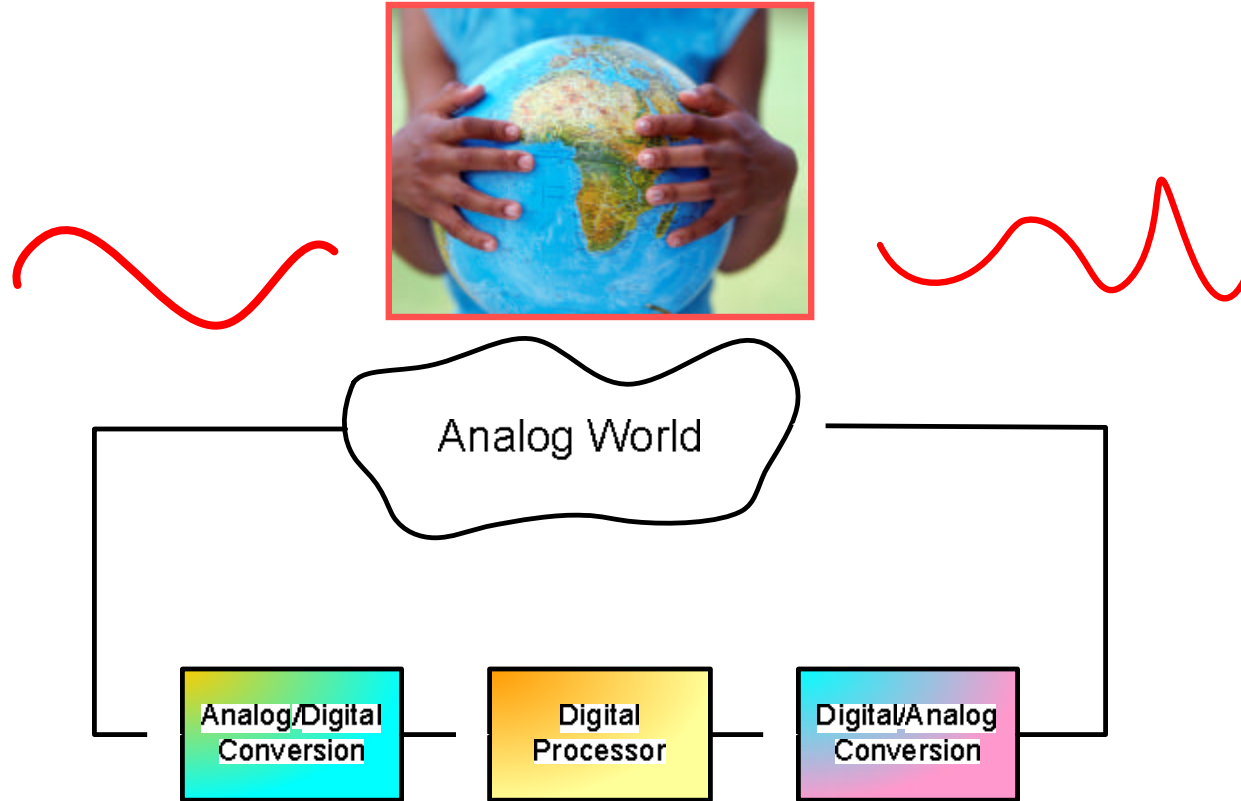
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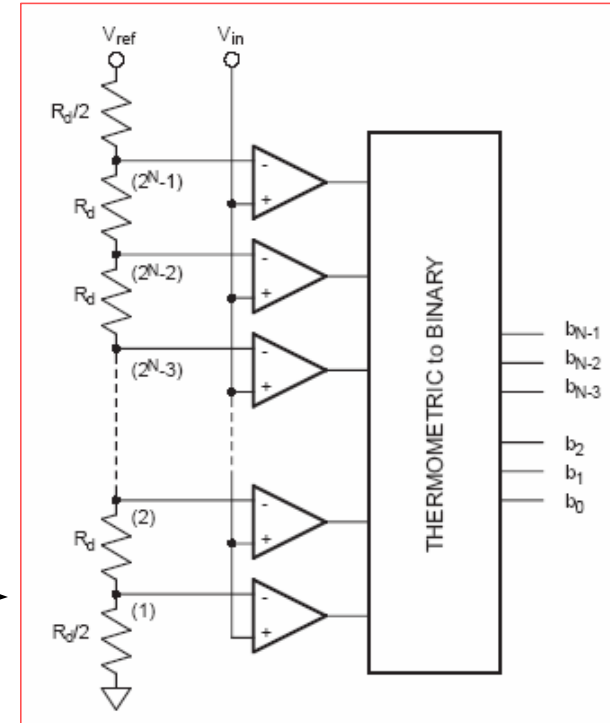
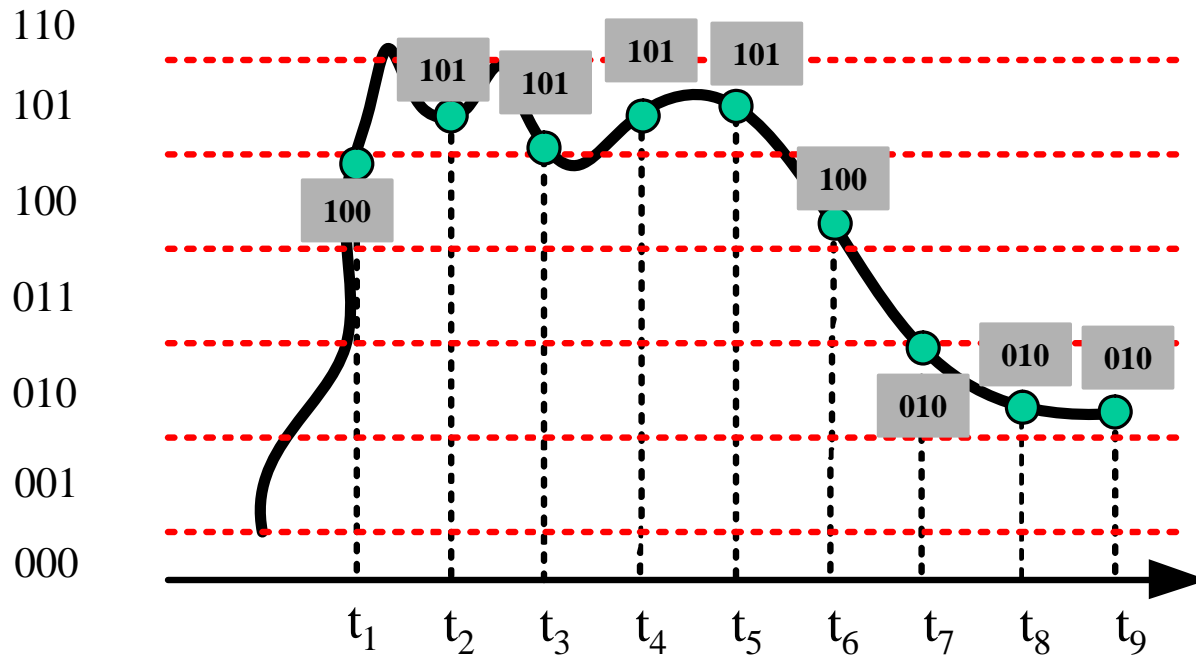
IEEE SSCS Dallas Chapter, June 2007

Why Analog to Digital Conversion?



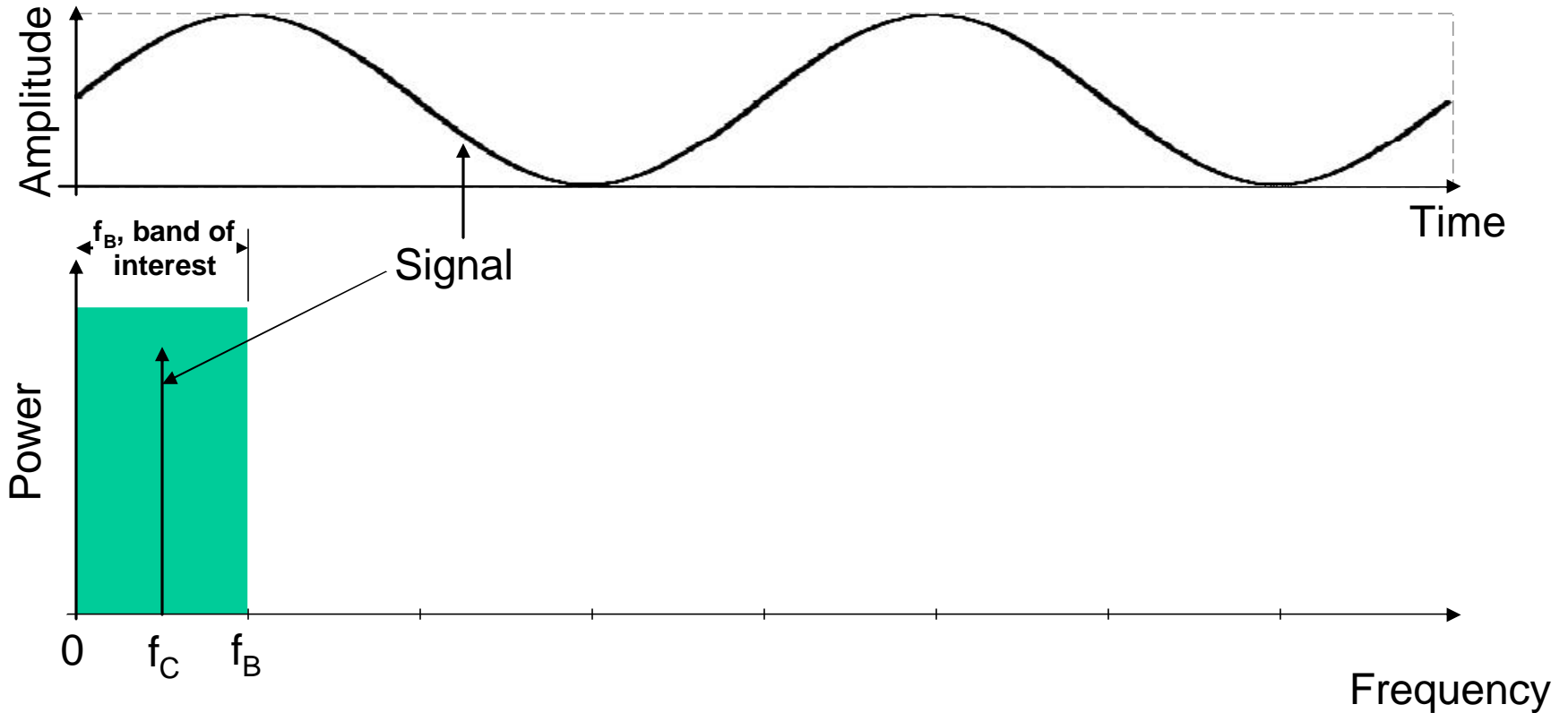
- ✓ Naturally occurring signals are analog signal
- ✓ Human beings perceive and retain information in analog form
- ✓ BUT, Analog signal is more sensitive to noise than digital signal

How Analog to Digital Conversion?



1. Sample analog signal
2. Quantize sampled analog signal \rightarrow Quantization noise
3. Faster sampling time, better accuracy
4. Higher quantization levels, better accuracy

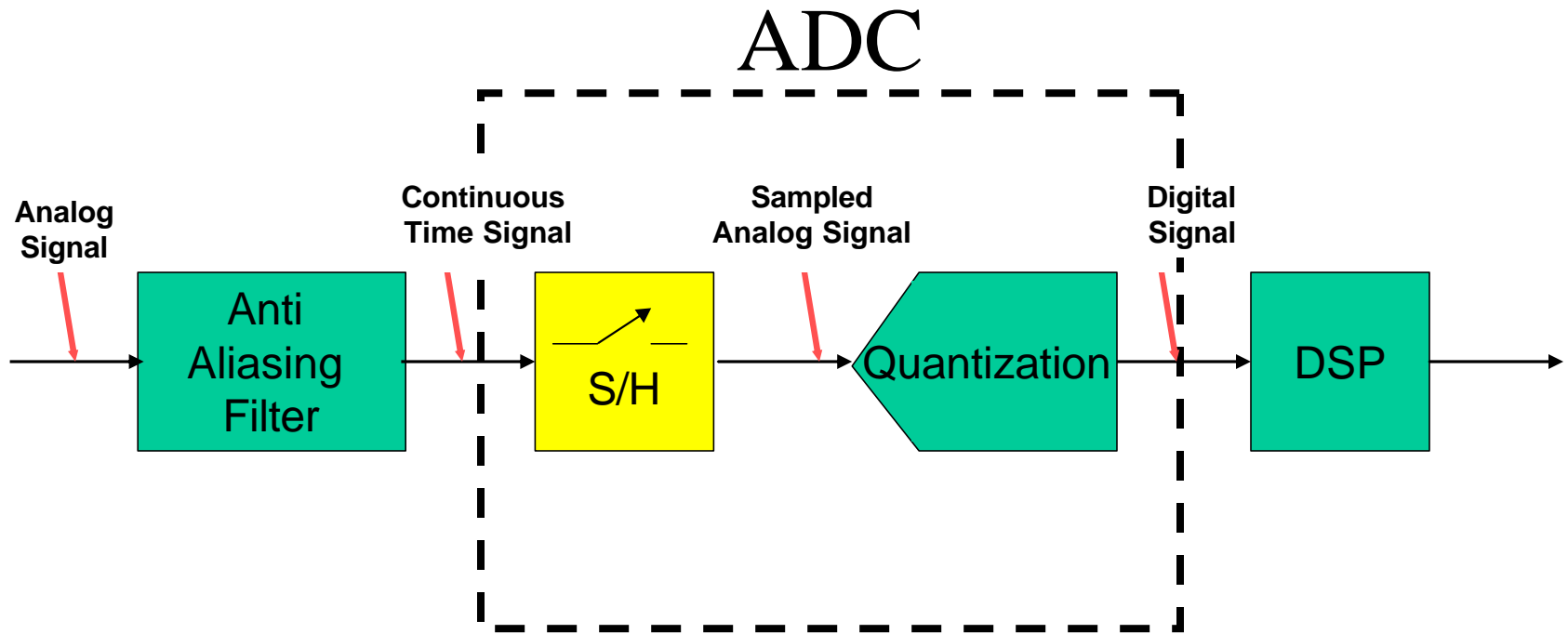
Continuous Time Signal



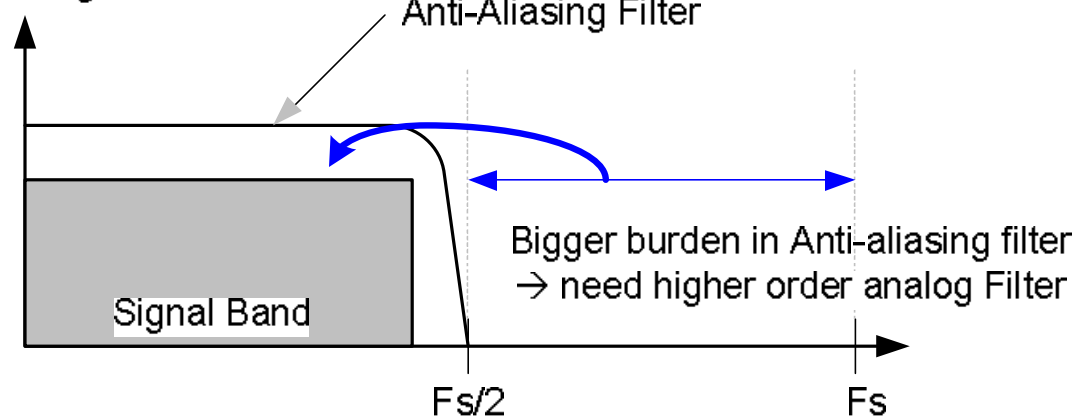
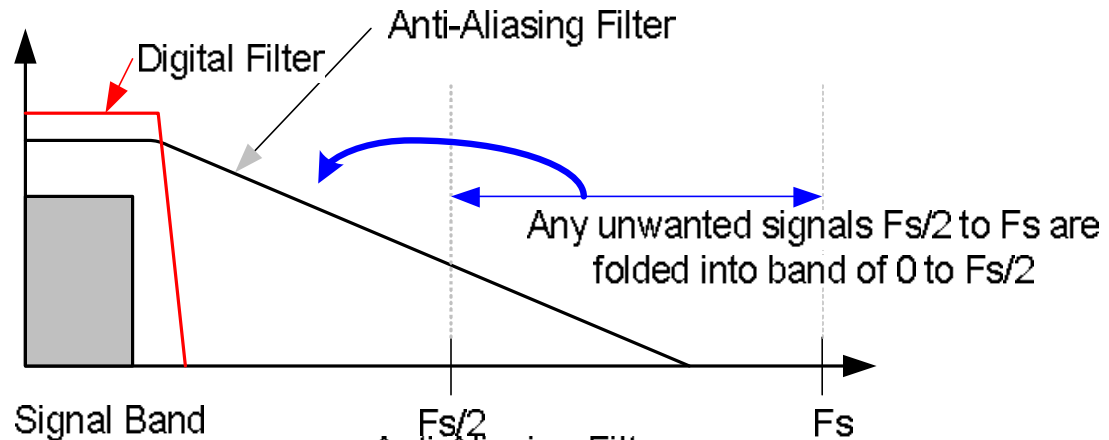
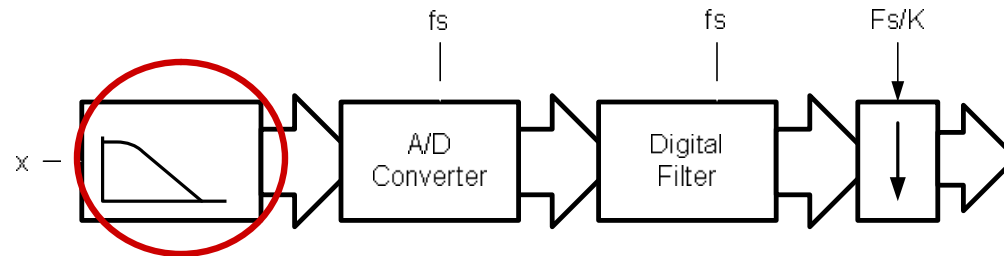
Signal frequency, f_C = band of interest, f_B (Maximum frequency of the signal)



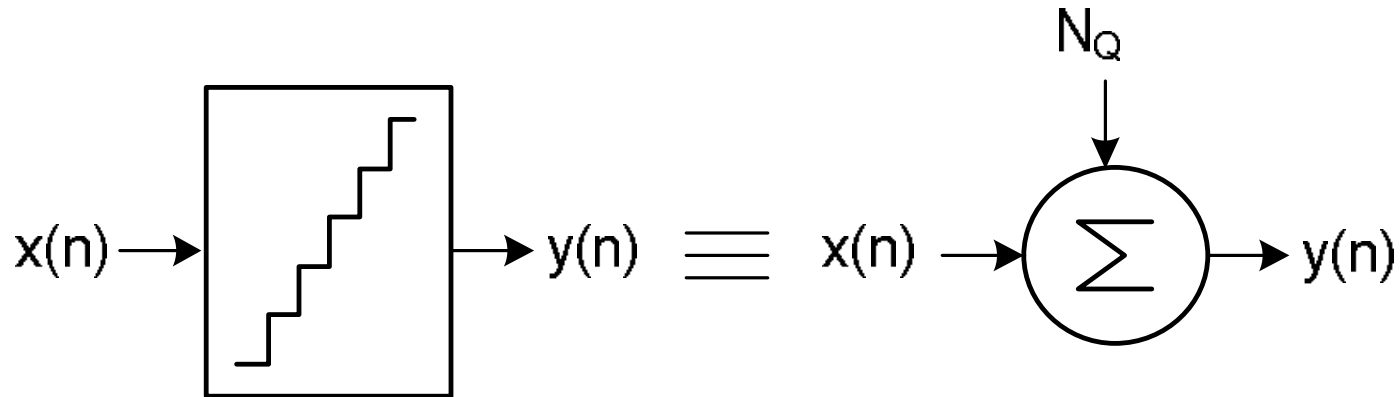
Typical Architecture for Analog to Digital Conversion



Nyquist Rate vs. Oversampled

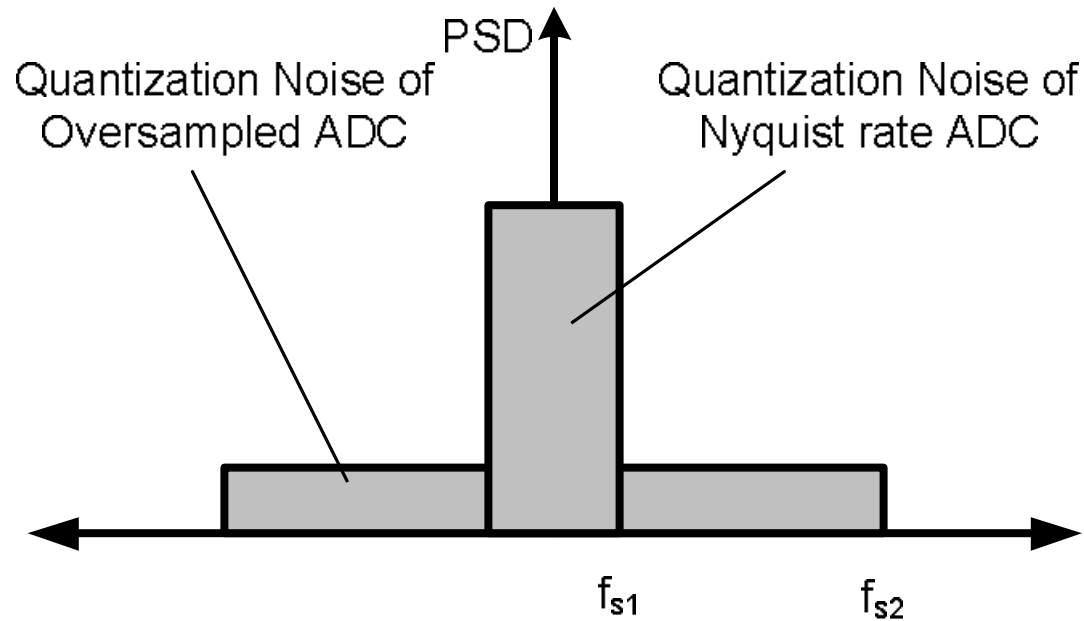


Modeling of Quantizer



- **Quantizer is non-linear building block**
 - Need modeling for simplifying the analysis
- **White additive noise assumptions**
 - It is not fulfilled in many applications, However
 - It makes analysis easy and makes possible the use of z-transformation

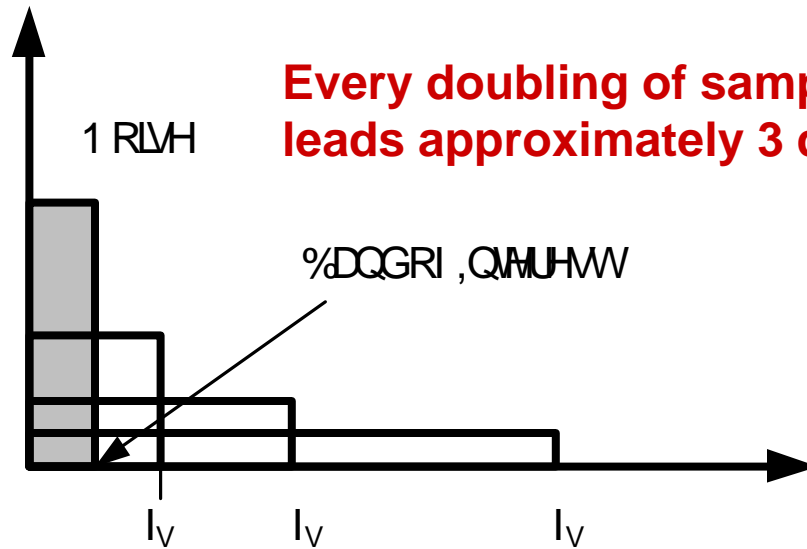
Quantization Noise



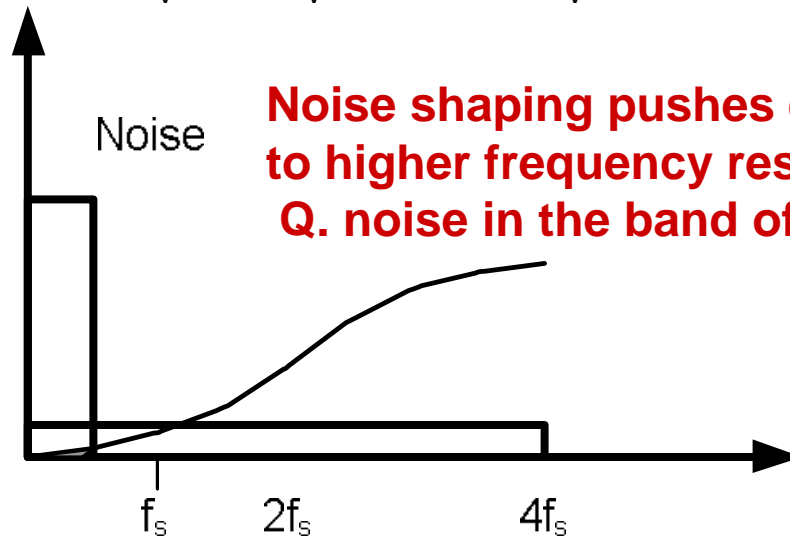
- **Quantity of in-band noise depends on the over-sampling ratio**
 - $SNR = 10\log(s_x^2) - 10\log(s_n^2) + 3.01r(\text{dB})$, where
 - s_x^2 and s_n^2 are input signal power and in-band noise power respectively, and
 - r is defined by over-sampling ratio, $f_s/2f_b=2^r$

Pervez M. Aziz, "An overview of sigma-delta converters," IEEE Signal processing Magazine, pp 61-84, Jan. 1996

Over-sampling and Noise Shaping

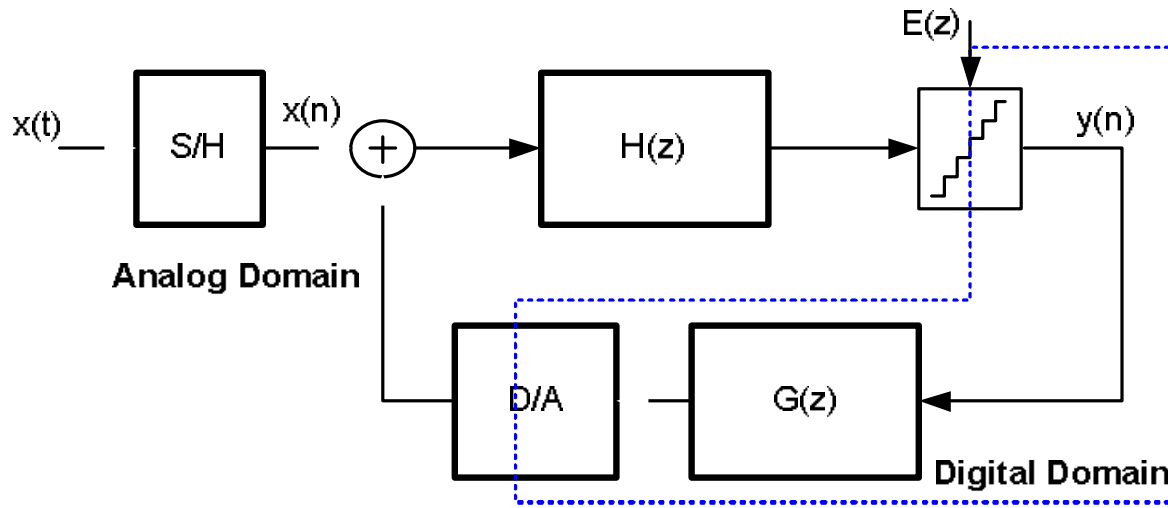


Every doubling of sampling frequency leads approximately 3 dB enhancement in SNR



Noise shaping pushes quantization noise to higher frequency resulting in suppressing Q. noise in the band of interest

How to Shape the noise?



$$Y(z) = \underbrace{\frac{H(z)}{1+H(z)G(z)}}_{\text{STF}} \times X(z) + \underbrace{\frac{1}{1+H(z)G(z)}}_{\text{NTF}} \times E(z)$$

If $H(z) = z^{-1}/1-z^{-1}$ and $G(z)=1$, NTF and STF will be:

$$\text{NTF} = \frac{Y(z)}{E(z)} = 1 - Z^{-1}$$

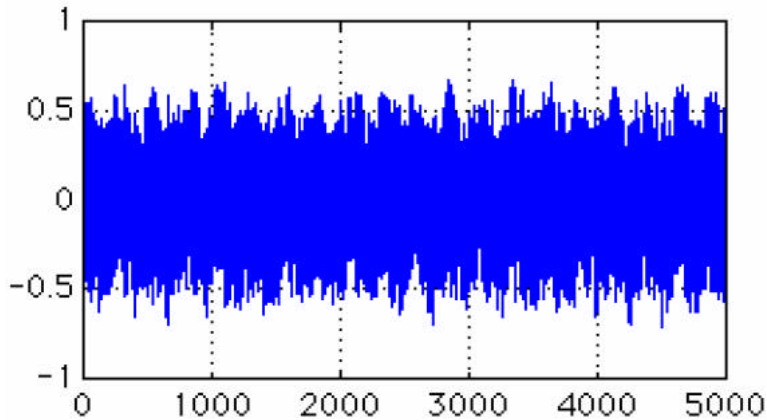
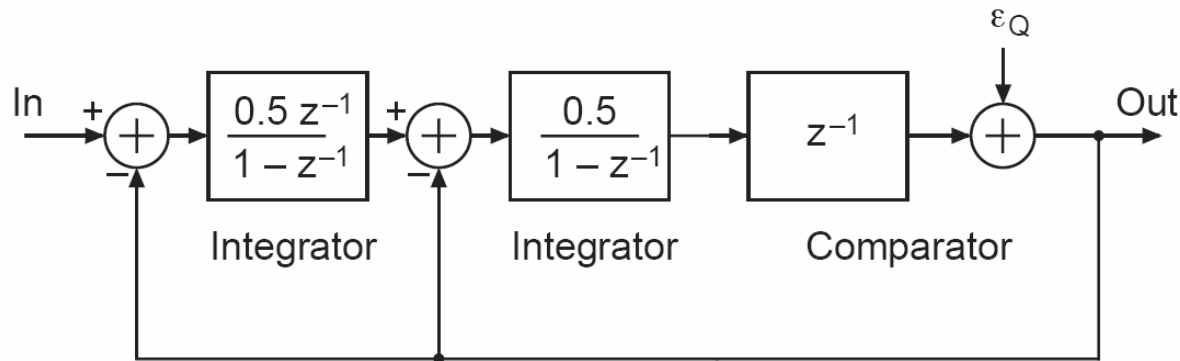
$$\text{STF} = \frac{Y(z)}{X(z)} = Z^{-1}$$



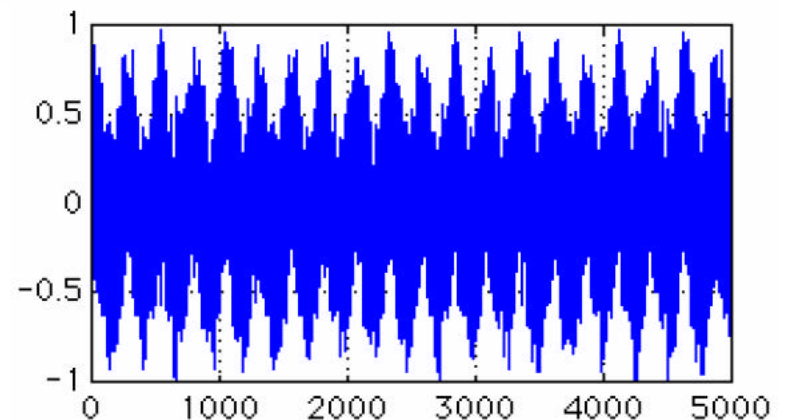




Example, 2_{nd} order Sigma-Delta ADC



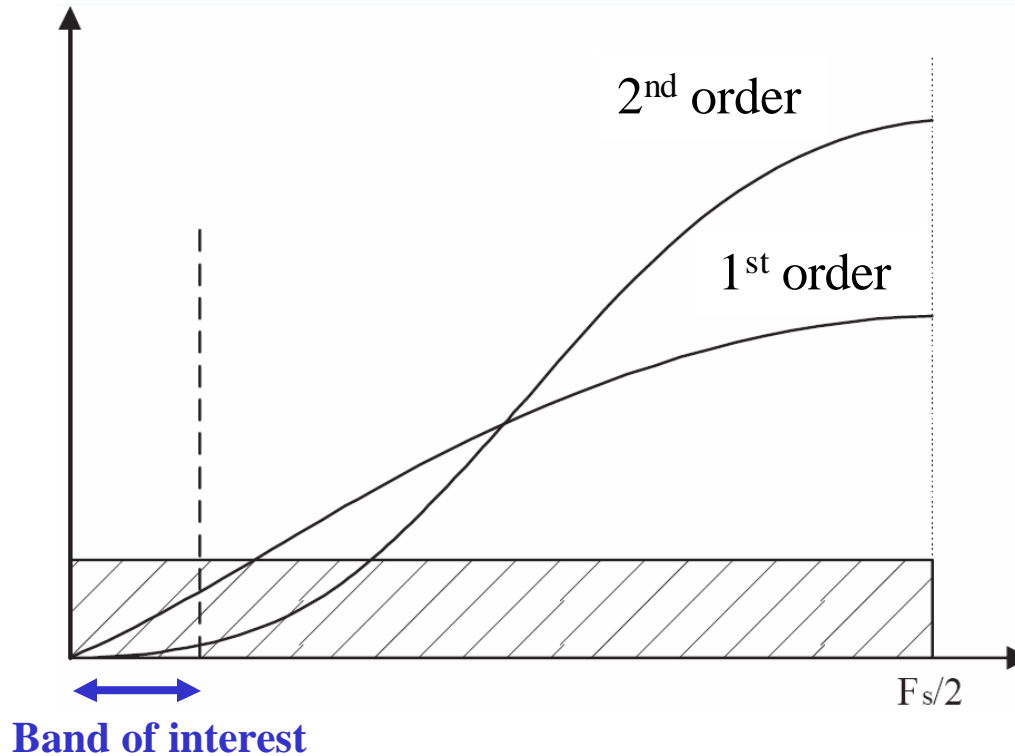
Output of the 1st integrator



Output of the 2nd integrator

- ✓ The dynamic range at the output of the two integrators is limited
- ✓ Input signal attenuation by 6 dB

Noise Shaping



In-band quantization noise is suppressed more with 2nd order

Single-bit or Multi-bit ? S

Single Bit

- Feedback DAC inherently **linear**. So no HD distortion.
- **Need a faster Amplifier**
- **Lower SQNR** for a given modulator order

Multi Bit

- Gives **higher SQNR**
- **Relaxed opamp** specs due to smaller step size
- **DAC non-linearity** is a performance limit
- Require dynamic element matching

Summary

- **Sigma-delta ADC provide trade-offs between:**
 - Power consumption,
 - Over-sampling ratio (*OSR*)
 - System performance (*SNR*)
- **High OSR implies:**
 - Lower number of quantization levels
 - Lower modulator order, but
 - More demanding settling requirements for the analog building blocks

A Sigma-Delta ADC with a built-in Anti-aliasing filter for Bluetooth receiver in 130 nm digital process

Jinseok Koh

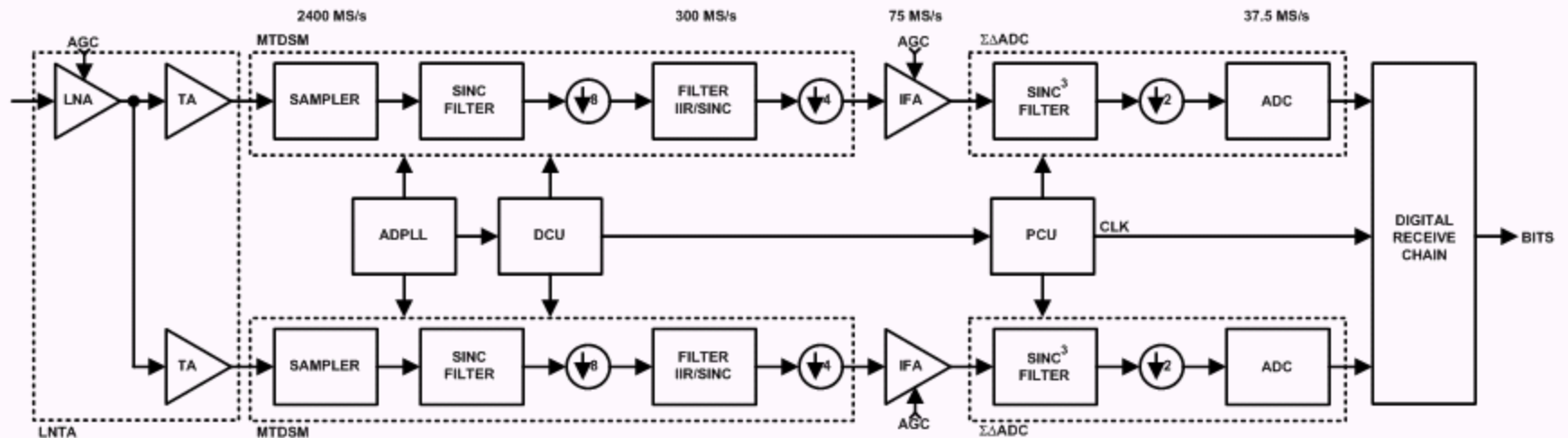
Wireless Analog Technology Center

Texas Instruments Inc.

Dallas, TX

Published in CICC2004

Introduction

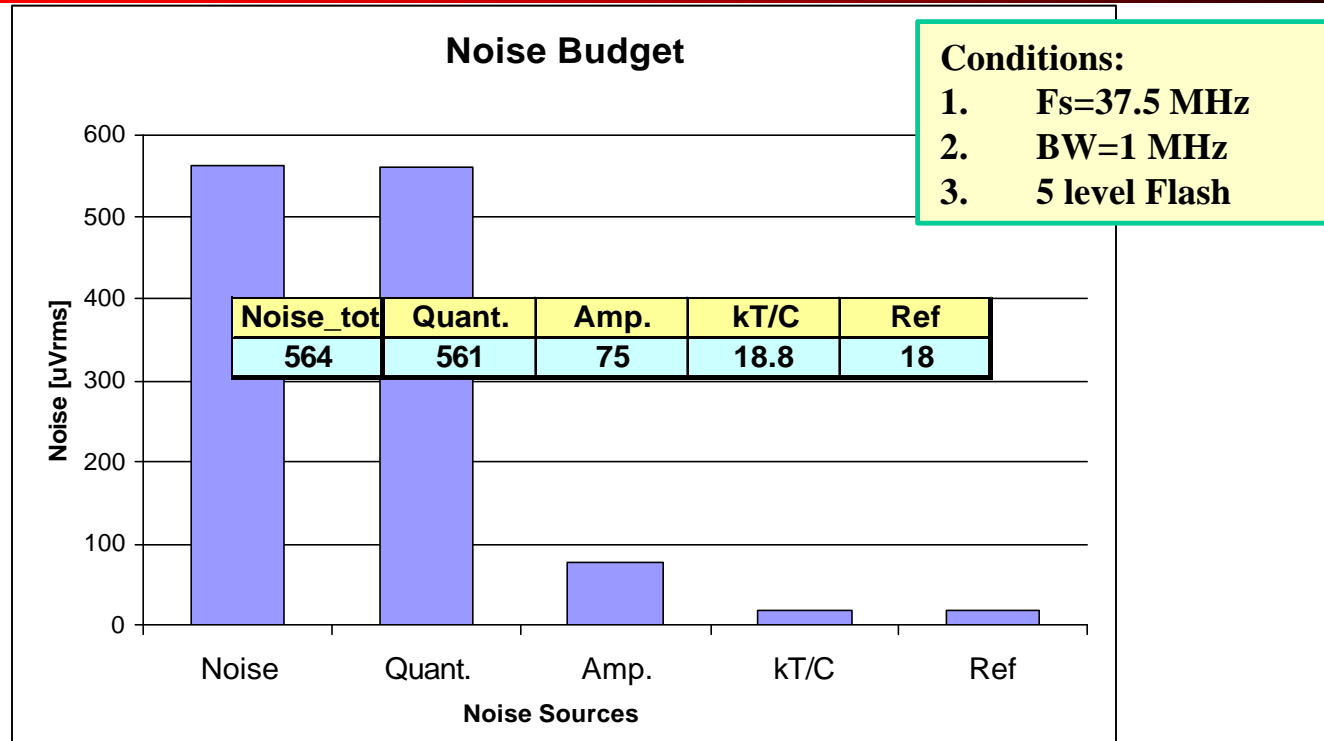


- RF input signal is amplified by two stage Amplifier, LNA and TA.
- TA output is down converted and filtered by Direct-Sampling Mixer (DSM).
- IFA amplifies mixer output signal operating at 75 Mhz.
- Sigma-Delta ADC converts 75 MHz IFA output to 37.5 MHz digital words.

ADC Requirements

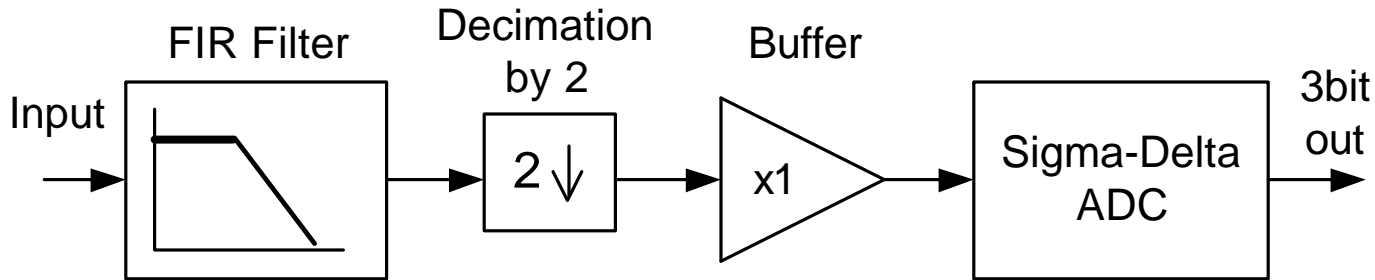
- **60 dB Dynamic range at 1 Mhz signal bandwidth**
 - 2nd order sigma-delta ADC
 - 5 level quantizer
 - 37.5 MHz sampling frequency.
- **Gain Control**
 - 0 dB and 14 dB gain option is required for system AGC function.
- **Low Power consumption**
- **Low cost**

Noise budget



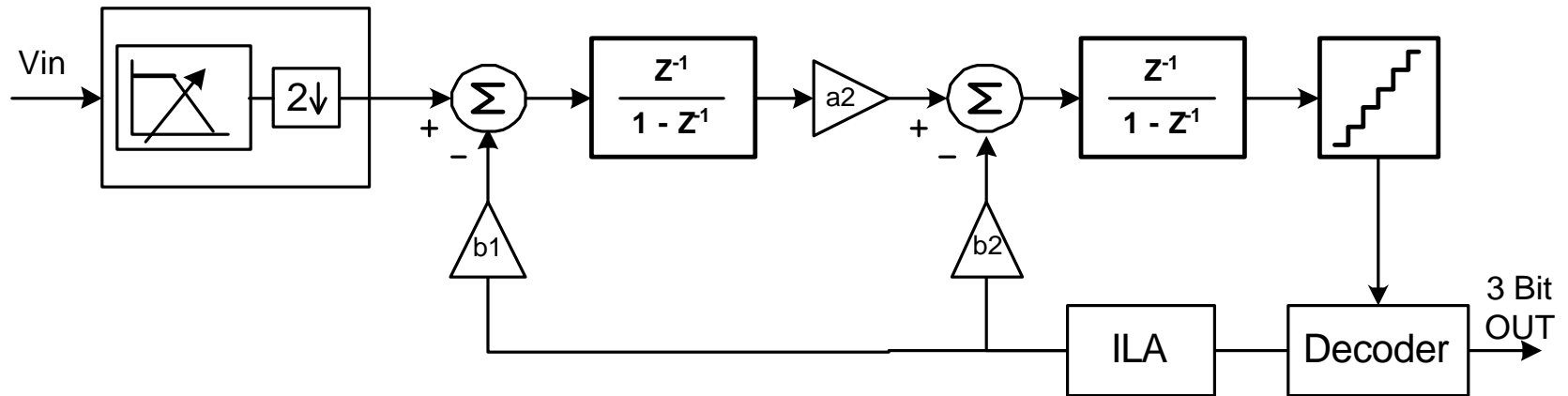
- **Quantization noise is a dominant noise source.**
 - Unit capacitance element is selected based on considering mismatch effect.
 - Noises from amplifier and reference buffer are not critical.
 - Power consumption of amplifier is minimized since noise from it is negligible compared to the high in-band quantization noise.

Required building blocks



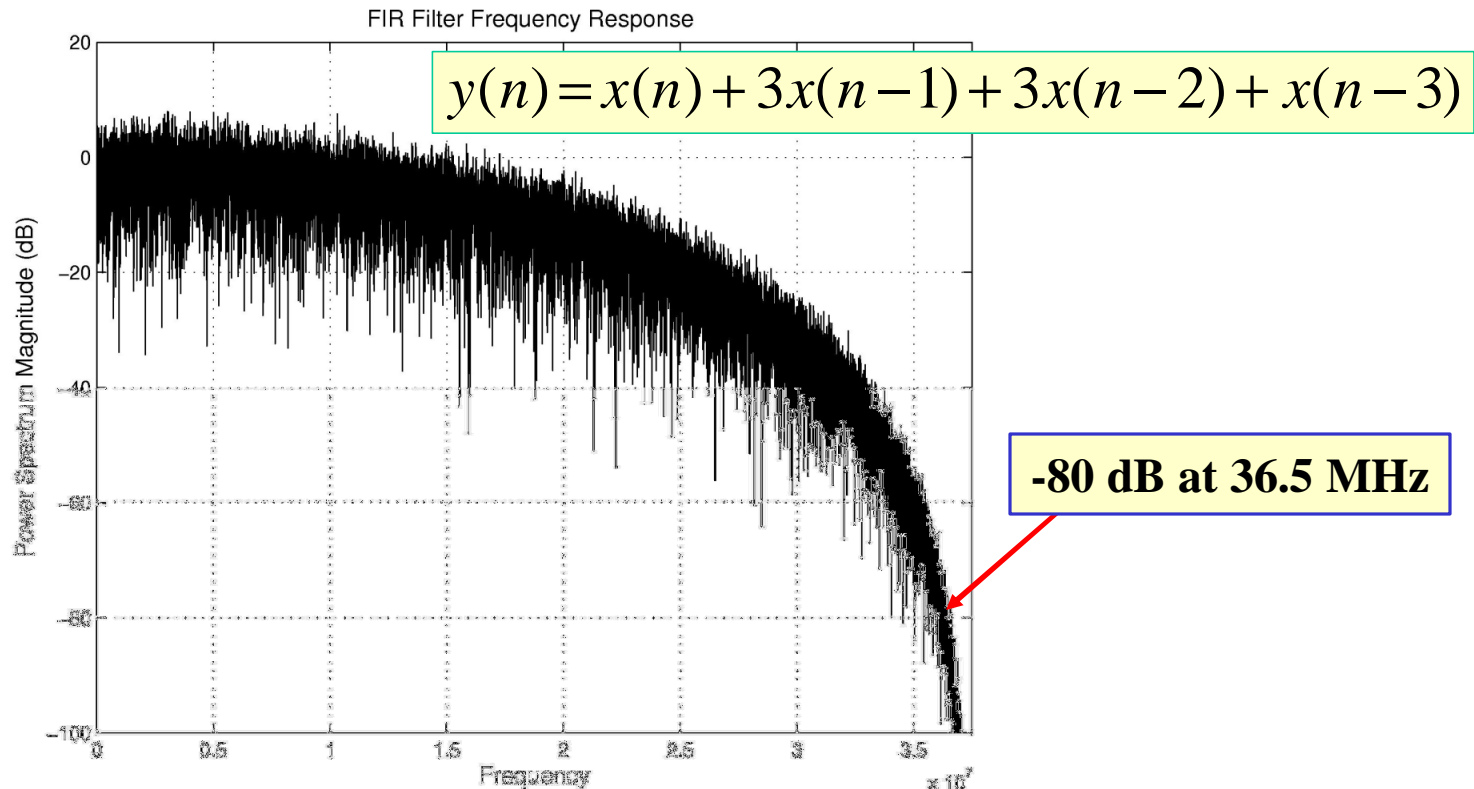
- Based on power consumption and noise analysis, following functions are required.
 - **Decimation by Two**: sampling frequency 37.5 MHz can provides enough Dynamic Range utilizing 5 level flash ADC.
 - **Anti-alias filtering**: Decimation by two function causes folding noise.
 - **Buffering**: buffer amplifier is required to avoid charge sharing between Switched capacitor FIR filter and sampling circuits in Sigma-Delta ADC.

Proposed Architecture



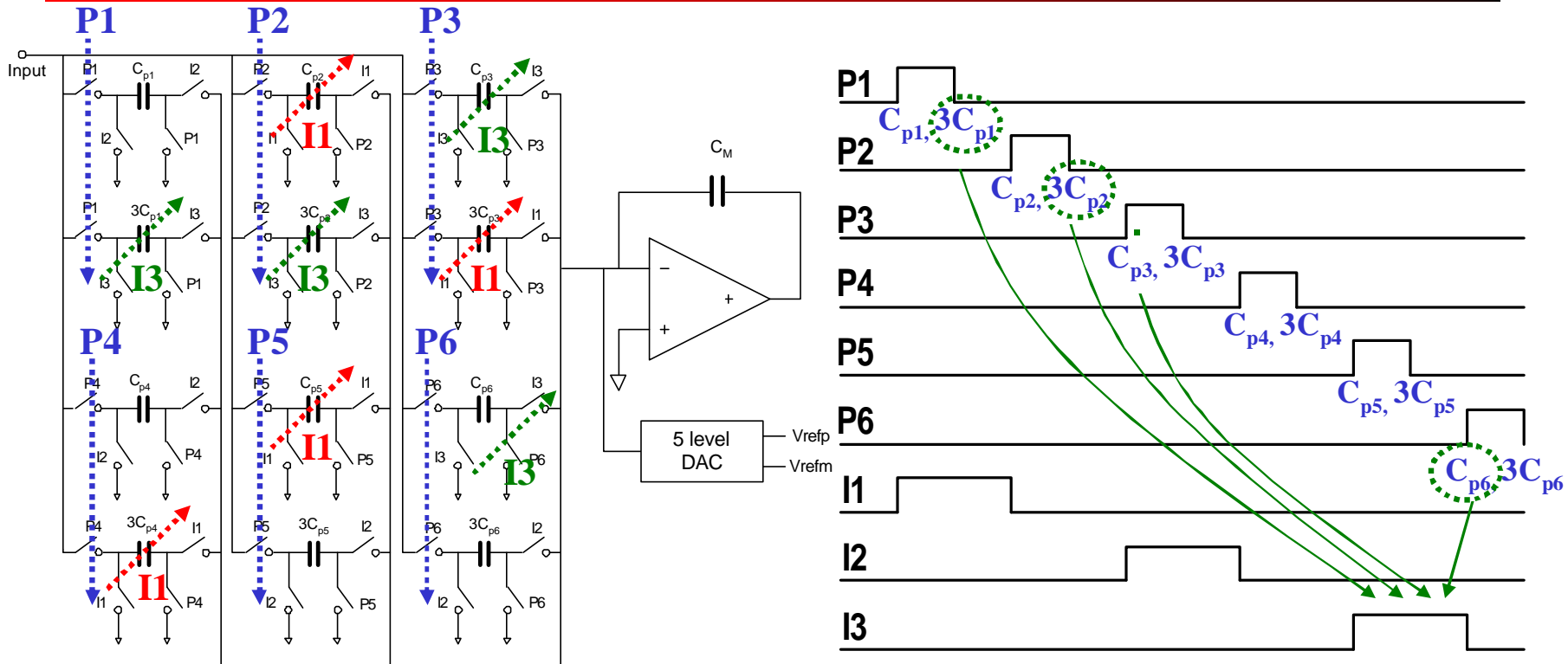
- **Decimation, anti-aliasing filtering is merged with sampling circuits.**
 - Saved power consumption and silicon area since it avoids the buffer.
- **Second order Sigma-Delta ADC with 5 level flash.**
- **ILA DEM is used to suppress mismatch energy from DAC in feedback loop.**

FIR Anti-aliasing Filter



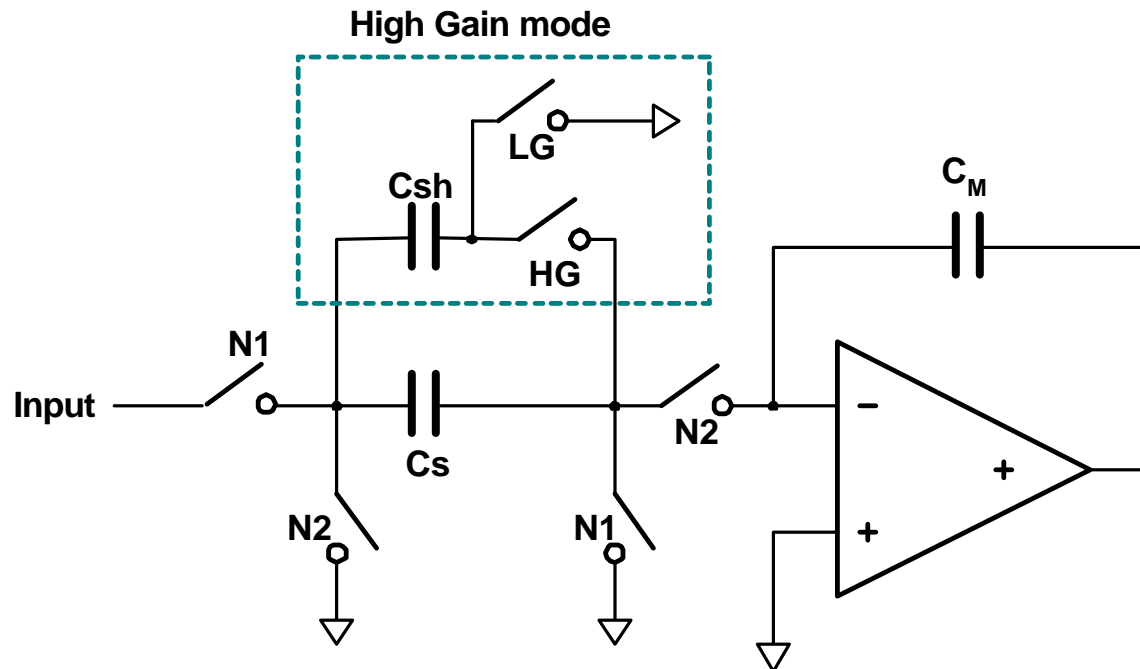
- 60dB attenuation is required to suppress folding noise by system simulations.
- Third order FIR filter is chosen and provides 80 dB attenuation at folding frequency band edge.

FIR Anti-aliasing Filter and Decimation



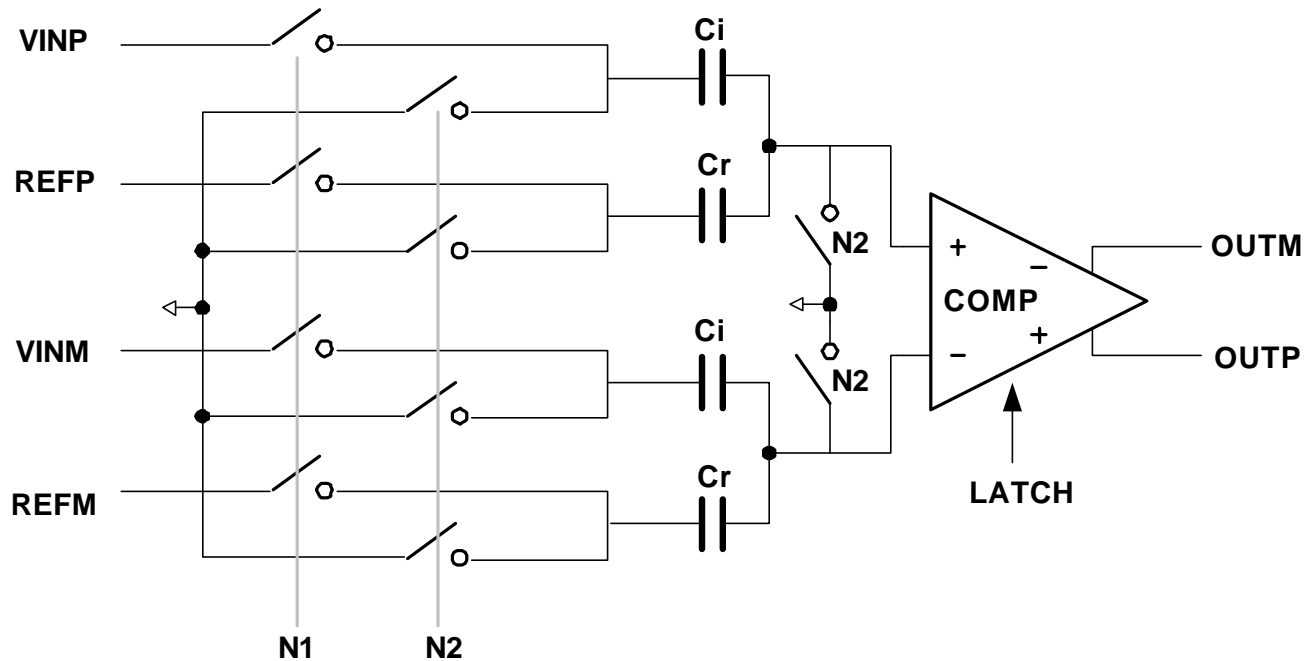
- 6 phase clock signals are utilized to implement FIR filter.
- On P_i phase, input is sampled at C_{p_i} and $3C_{p_i}$ capacitors,
- On I3 phase, C_{p_3} , $3C_{p_2}$, $3C_{p_1}$ and C_{p_6} is dumped into integrating capacitor.

Gain control



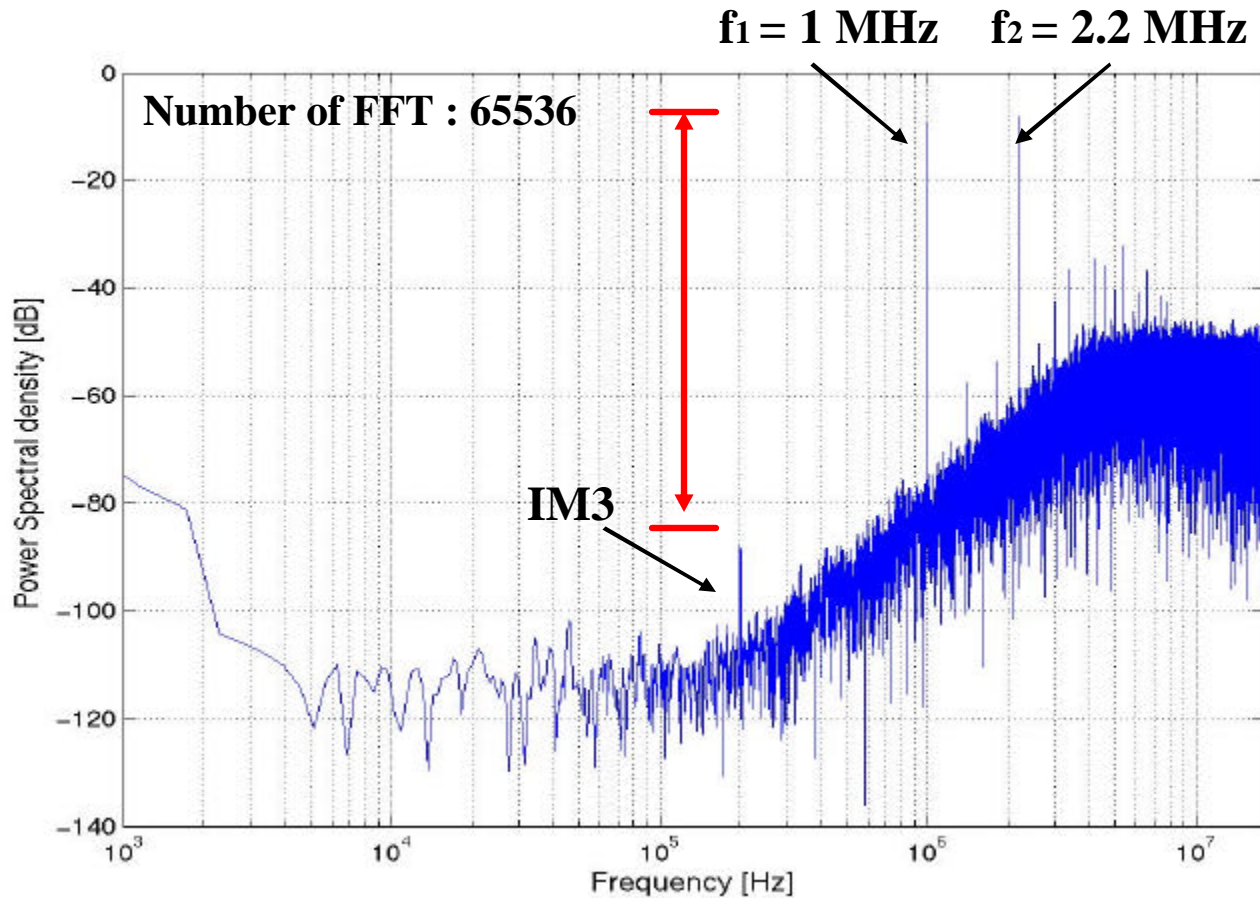
- Gain control function is implemented in FIR sampling block by adding the high gain mode switched capacitor circuits in parallel with each capacitor in SC FIR filter.
- Gain is defined by the ratio between sampling capacitors and integrating capacitor (C_M).

Comparator



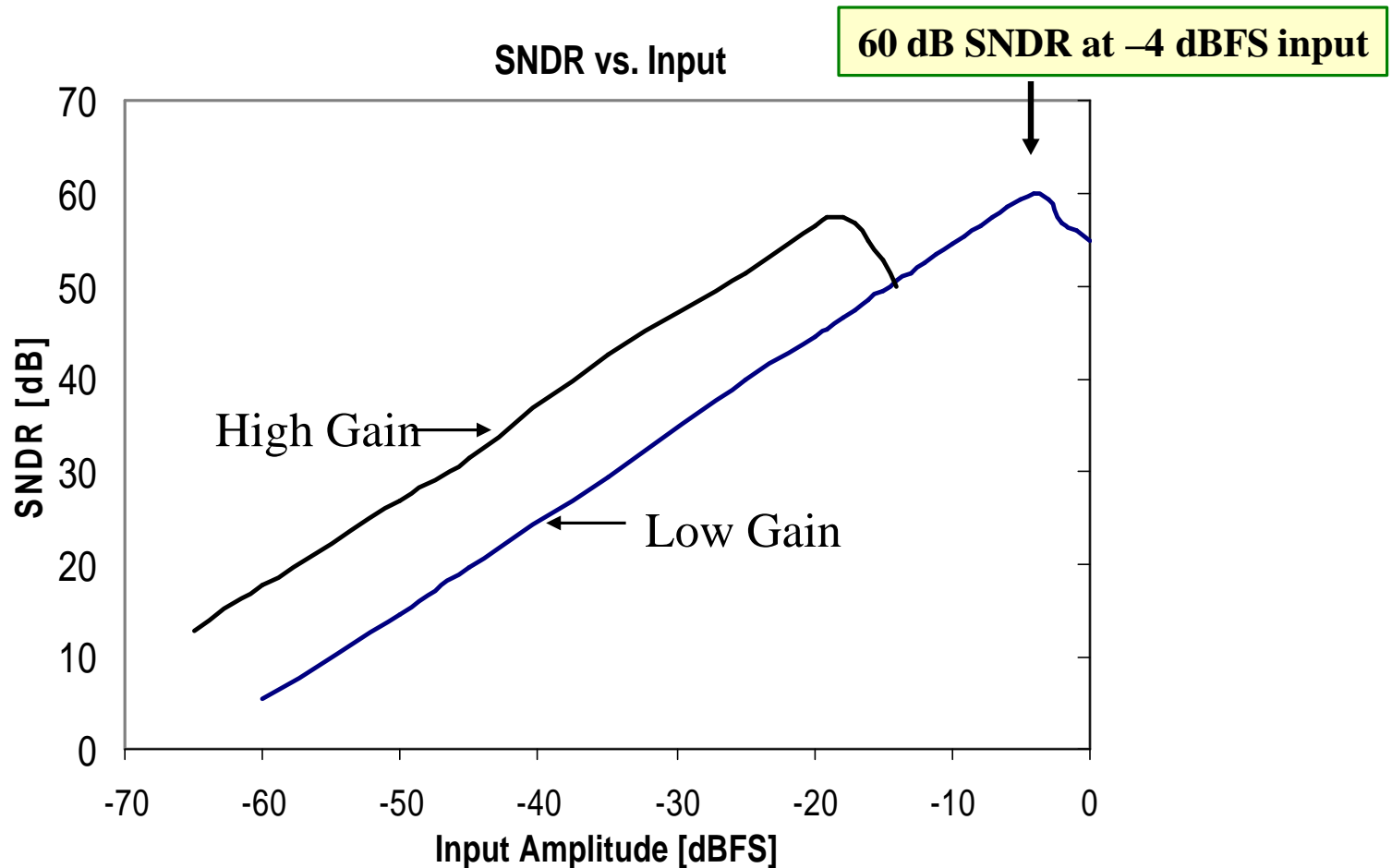
- **Switched capacitor comparator is used to build 5 level quantizer.**
- **Capacitor ratio between C_i and C_r is chosen to have threshold voltage for each comparator.**
- **Capacitor size is optimized to be minimum considering decision speed, resolution (mismatch) and offset.**

Two Tone Measurements



- -8 dBFS sine signals at 1 MHz (f_1) and 2.2 MHz (f_2) are applied.
- -80 dBc IM3 shows at 200 kHz.

Measured SNDR



- **Peak SNDR for high gain mode is smaller since harmonics come earlier than low gain mode due to amplifier speed.**

Performance summary

Technology	130nm Digital CMOS Process
Sampling Frequency	37.5 MHz
Signal Bandwidth	1 MHz
Peak SNDR1	60 dB
Peak SNDR2	57 dB
Dynamic Range	67 dB
Overall Dynamic Range	77 dB
Input Range	1.4 V_{pp} (differential)
Power Consumption	1.6 mW
Voltage Supply	1.58 V
Core Area	0.2 mm²

- **Sinusoidal signal at 360 kHz is used for performance measurements.**
- **Peak SNDR1 : when 0 dB gain option is selected.**
- **Peak SNDR2 : when 14 dB gain option is selected.**

Conclusion

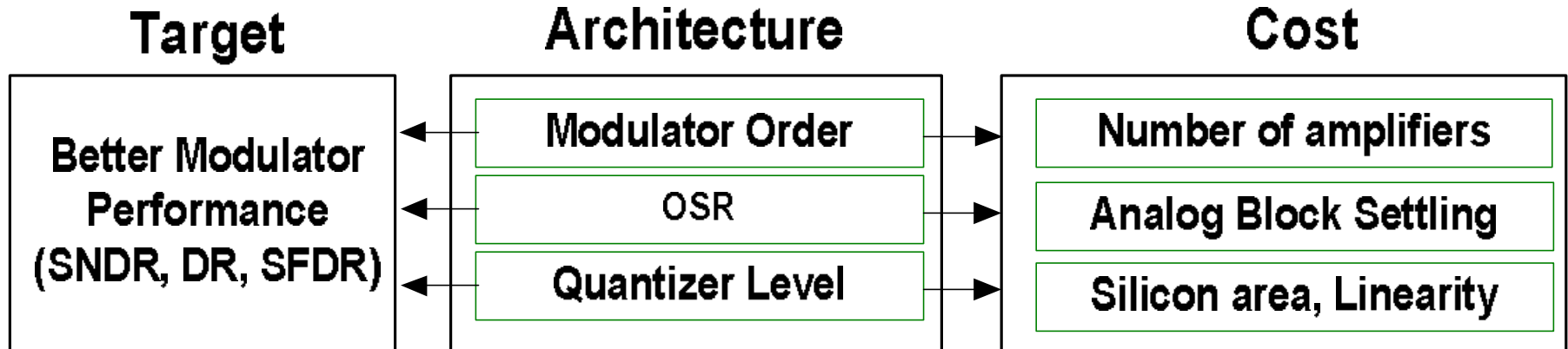
- **Second order 5 level Sigma-Delta ADC with built-in anti-aliasing filter is realized.**
- **Decimation by two function relaxed settling and slew rate requirement.**
- **SC FIR filter for anti-aliasing is merged with sampling circuit.**
 - **Achieved power saving and cost reduction**
- **Two step gain control increases overall Dynamic Range.**
 - **Relax the automatic gain control burden in bluetooth system.**
- **Building block parameters are optimized based on noise analysis and realized low power consuming ADC.**

**66dB DR 1.2V 1.2mW Single-Amplifier
Double-Sampling 2nd-order $\Sigma\Delta$ ADC for
WCDMA in 90nm CMOS**

**Jinseok Koh
Wireless Analog Technology Center
Texas Instruments Inc.
Dallas, TX**

Published in ISSCC2005

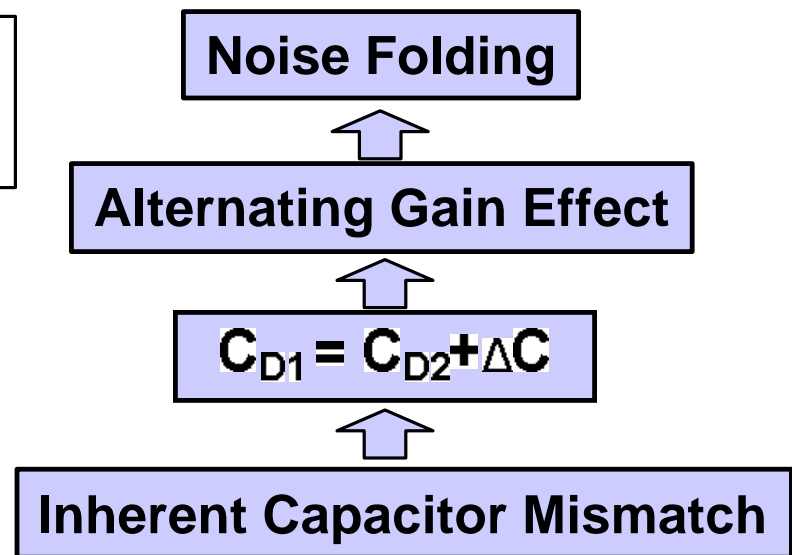
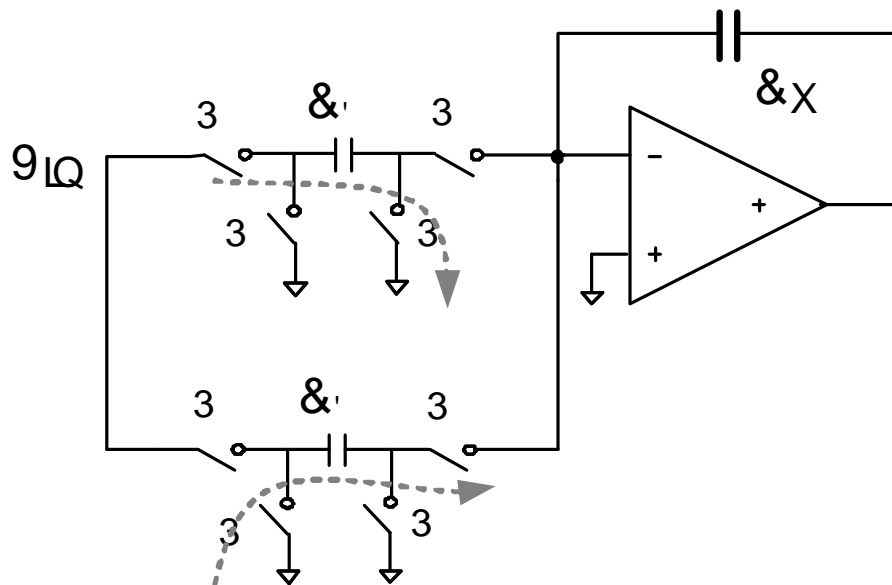
Objectives



- For a given performance requirement, power consumption and area are optimized by:
 - Increasing sampling frequency → Double sampling technique
 - Increasing modulator order → Single Amplifier topology
 - Higher number of levels in Quantizer → 5-level quantizer with ILA

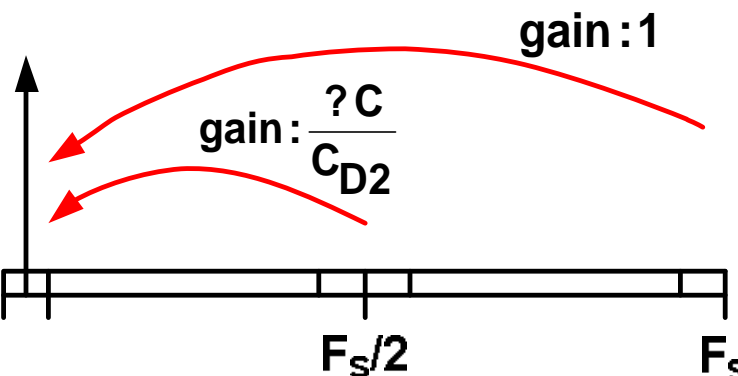
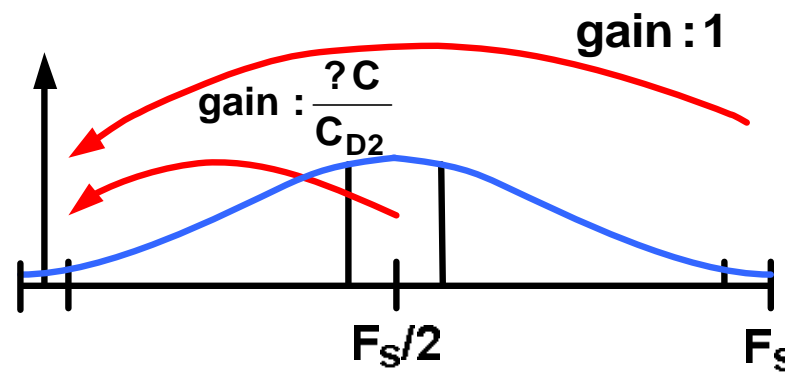
Double sampling

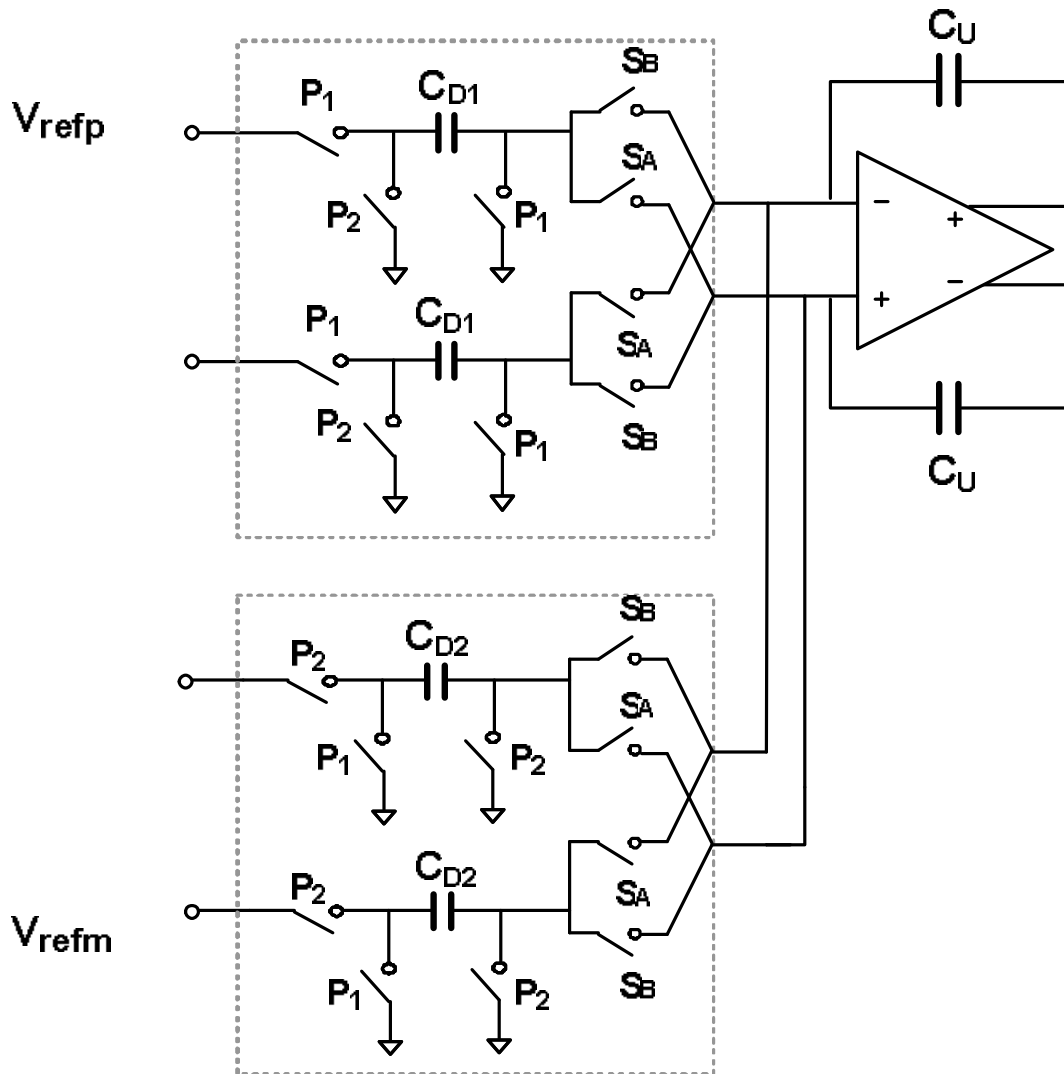
- **Advantages:**
 - Efficient technique to double the OSR
 - Doesn't need faster op-amp settling
 - Provides improvement of SQNR by $6n+3$ dB (n =order)
- **Disadvantage:**
 - Mismatch between capacitors creates noise folding



Noise Folding In Double Sampling

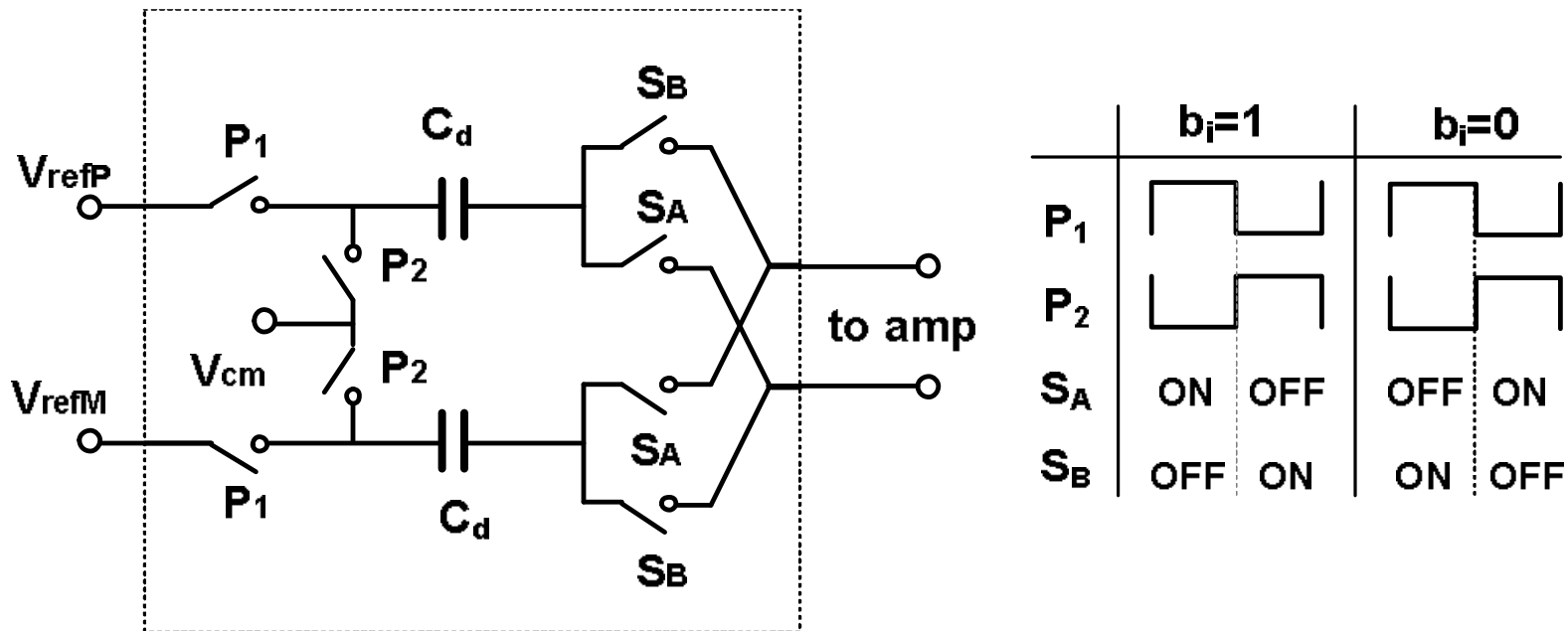
- Alternating gain effect
 - Noise at $F_s/2$ is folded into Signal bandwidth

Noise folding (Input sampling circuit)	Noise folding (DAC in feedback path)
 <ul style="list-style-type: none"> • Noise at $F_s/2$ is suppressed by <ul style="list-style-type: none"> - Anti-aliasing filter - Pre-filtering 	 <ul style="list-style-type: none"> • No filtering on quantization noise



Proposed SC DAC element for double sampling

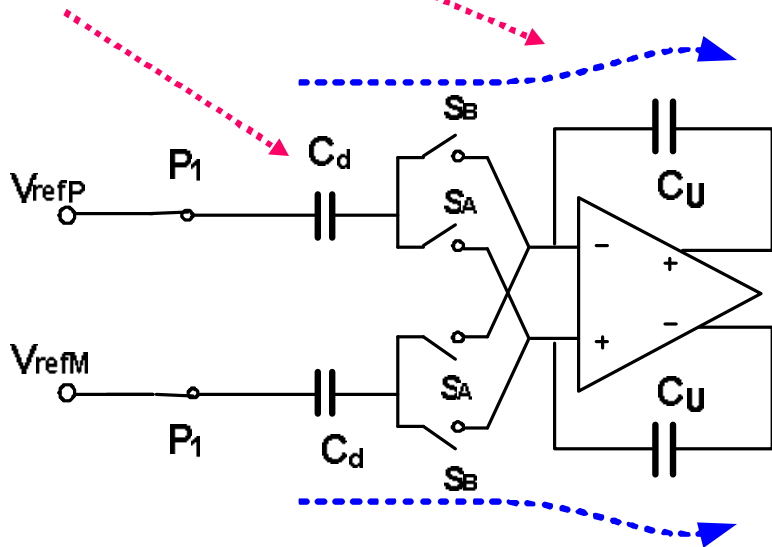
$$| \mathbf{B} = b_0, b_1, b_2, b_3,$$



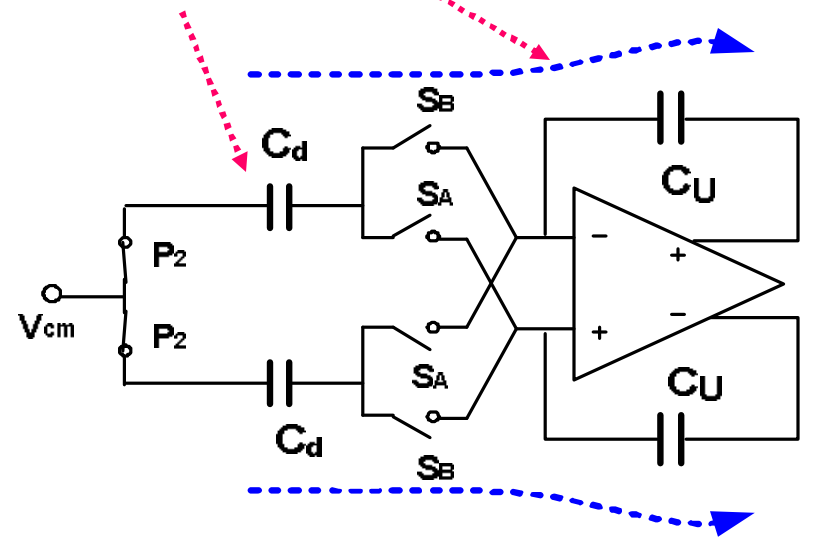
- Advantages of this approach vs. conventional approach:
 - Only one pair of capacitors needed
 - No “alternating-gain” effect
 - No additional circuitry needed for matching purposes

Operation of Proposed SC DAC element

$$|Q_d| = C_d(V_{\text{refP}} - V_{\text{refM}}) \quad |Q_u| = C_d(V_{\text{refP}} - V_{\text{refM}})$$

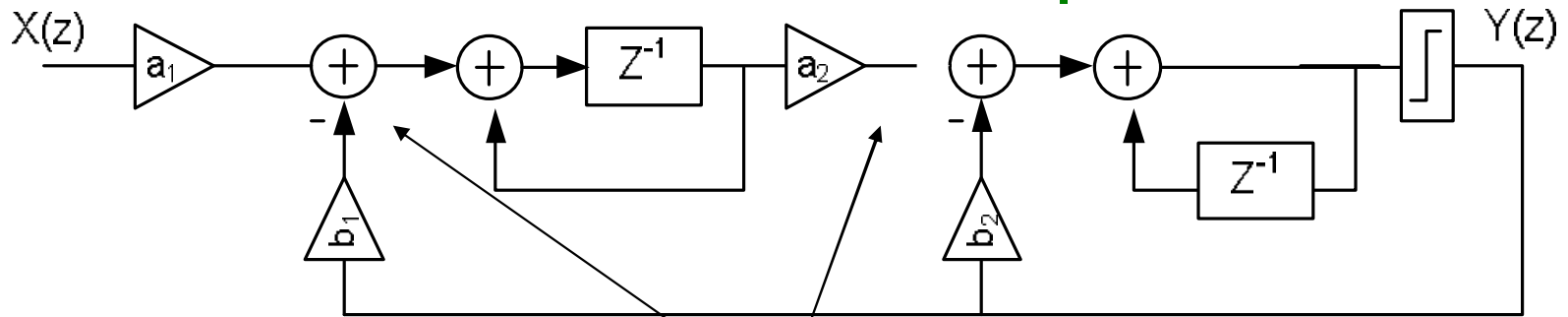


$$|Q_d| = 0 \quad |Q_u| = C_d(V_{\text{refP}} - V_{\text{refM}})$$



- On phase P_1 the charge transferred to Integrating Capacitor is:
 - $Q_u = C_d(V_{\text{refp}} - V_{\text{refm}})$
 - Q_u is equal to the charge stored into C_d
 - This charge will be used during next integration phase

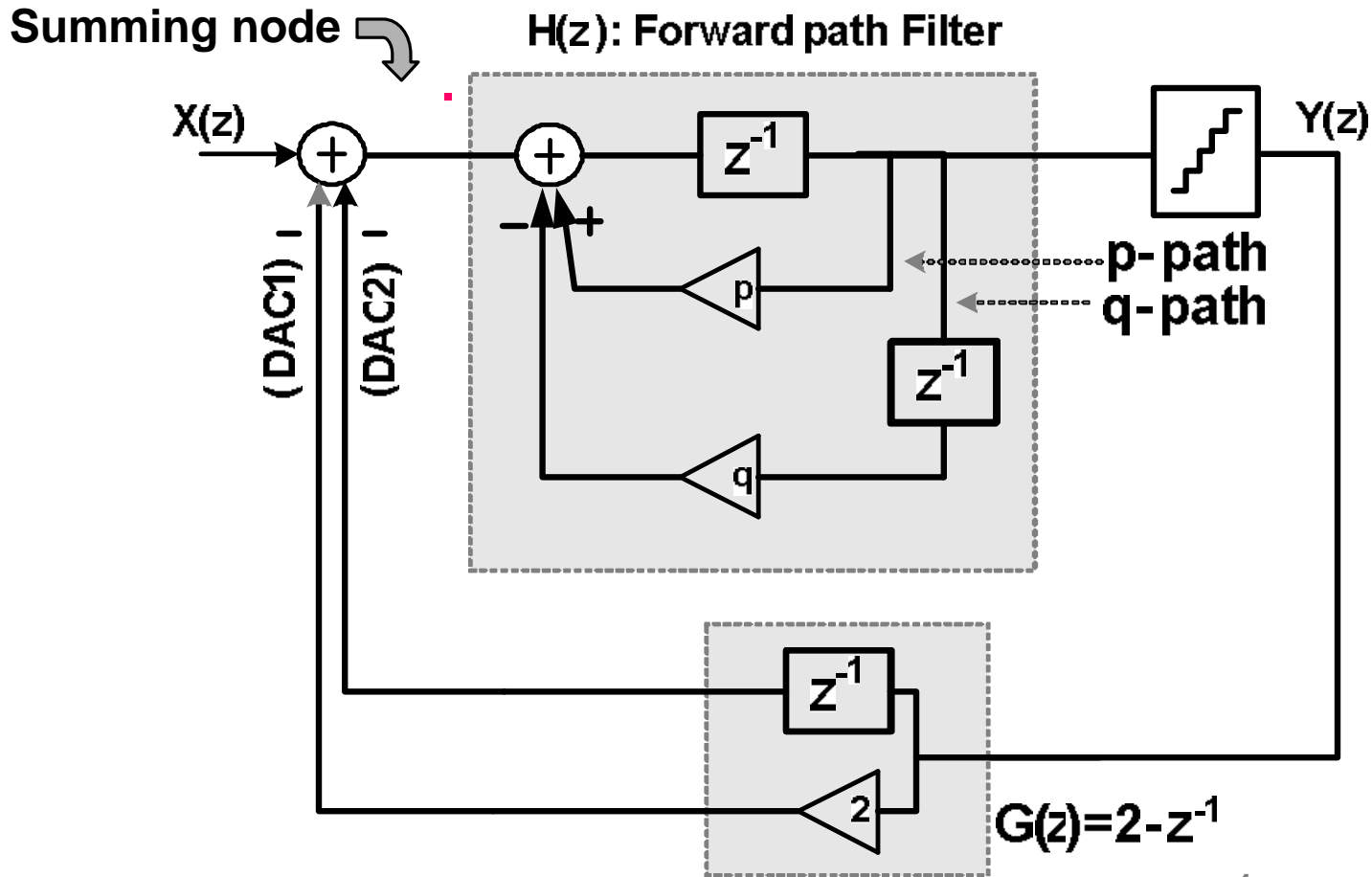
Conventional 2nd Order Sigma-Delta ADC



Each Summing Node requires an Amplifier

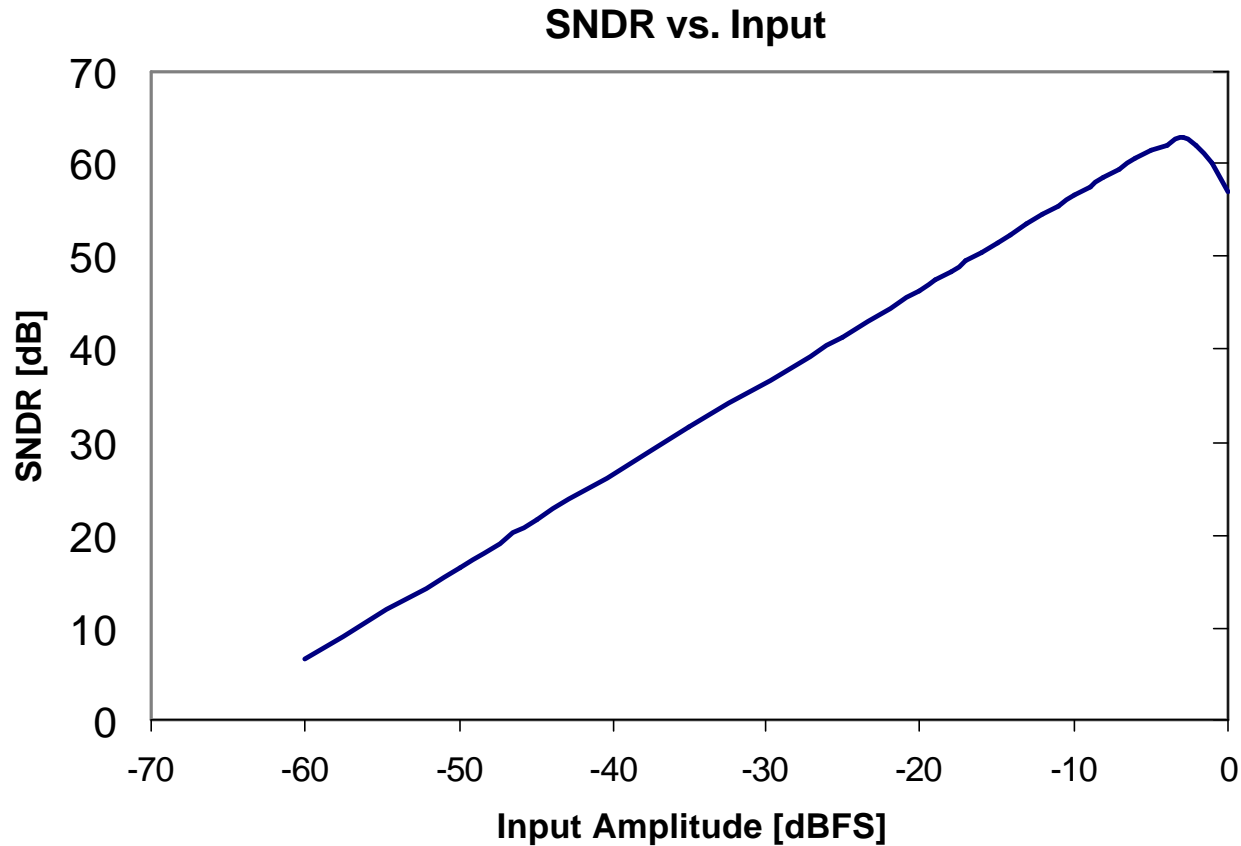
- **Conventional Sigma-delta ADC:**
 - Needs an amplifier per summing node
 - Poles and zeros are chosen by a_i and b_i , where $i=1,2$

Single Amplifier 2nd Order Sigma-Delta ADC



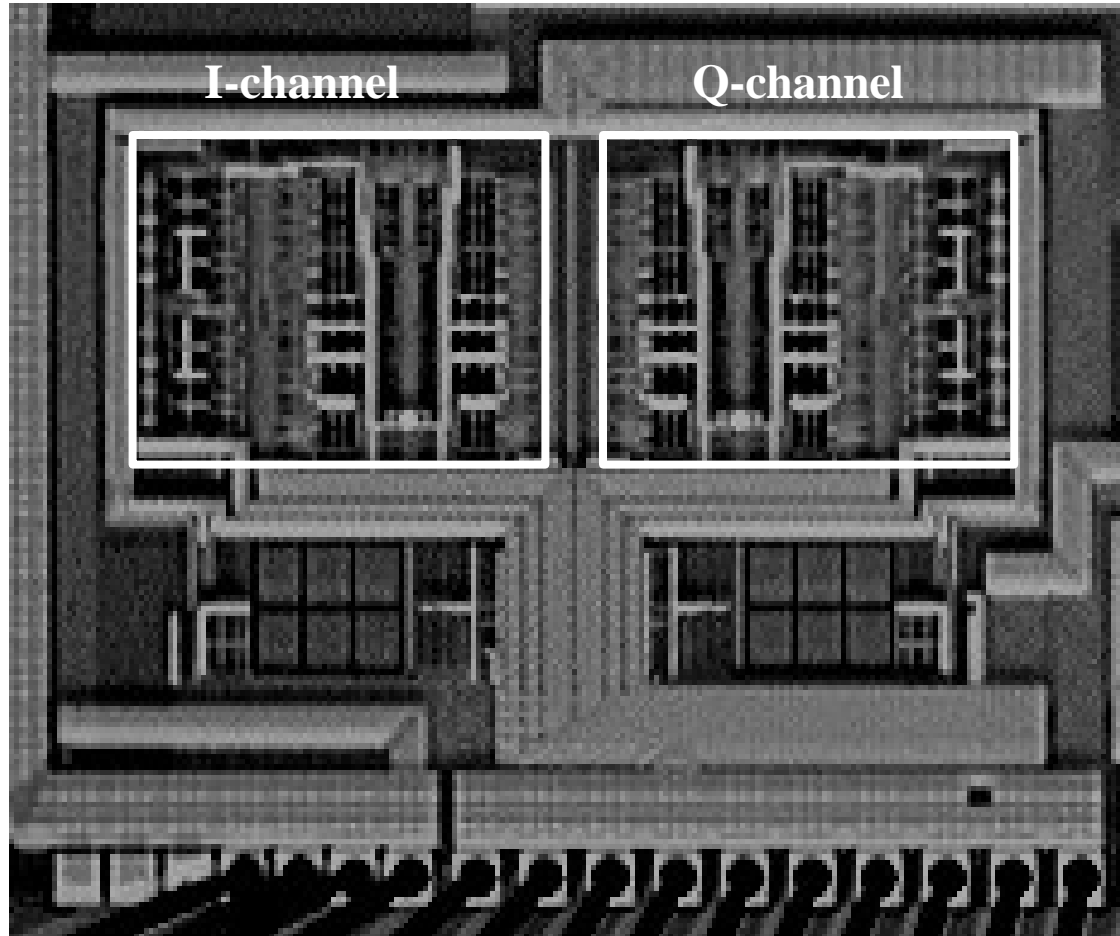
$$STF = \frac{z^{-1}}{1 - p \cdot z^{-1} - q \cdot z^{-2} + z^{-1}G(z)} \quad NTF = \frac{1 - p \cdot z^{-1} - q \cdot z^{-2}}{1 - p \cdot z^{-1} - q \cdot z^{-2} + z^{-1}G(z)}$$

SNDR vs. Input power



- **63dB peak SNDR happens at -3dBFS input sinusoidal**

Die Photography for dual channel ADCs



- Implemented in 90nm 5 metal digital CMOS process

Performance Summary

Technology	90 nm Digital CMOS
Signal Bandwidth	1.94 MHz
Clock Frequency	38.4 MHz
Sampling Frequency	76.8 MHz
Peak SNDR	63 dB
Dynamic Range	66 dB
Input Range	1.5 V_{pp} (differential)
Voltage Supply	1.2 V
Power Consumption	1.2 mW per ADC
Core Area	0.2 mm² per ADC

Conclusions

- **Second order 5 level Single Amplifier Sigma-Delta ADC with double sampling technique was realized in 90 nm CMOS.**
- **By using double sampling technique, OSR is doubled with no increase of power consumption and silicon area.**
- **Single-capacitor double-sampling DAC solved “alternating-gain” error effect.**
- **2nd order modulator is implemented using a Single-amplifier architecture. Higher order modulator is feasible.**
- **Low power consumption: 1.2mW for WCDMA, measured with a 1.2V power supply.**
- **66dB dynamic range was achieved in 1.94MHz bandwidth.**